

F-7094

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Toru MATSUMOTO et al.
Serial No. : (Not yet known)
Filed : (Concurrently herewith)
For : SEMICONDUCTOR TEMPERATURE
DETECTING METHOD AND ITS CIRCUIT
Group Art Unit : (Not yet known)
Examiner : (Not yet known)

Assistant Commissioner
for Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT (A)

Sir:

Preliminary to examination, please amend the above-identified patent application as follows:

IN THE CLAIMS:

Please amend the claim as shown rewritten below with amendments effected therein. Appendix I is attached hereto having marked versions of said claim with amendments indicated by brackets and underlining.

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7. (Amended) The semiconductor temperature detecting circuit according to Claim 3:

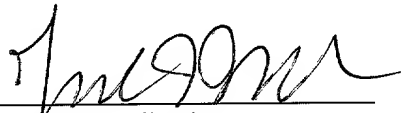
wherein the semiconductor substrate is of a conductive type of a P type or an N type.

REMARKS

This Preliminary Amendment is being submitted to avoid having a multiple dependent claim depend on another multiple dependent claim. It is respectfully requested that the first Office Action be directed to the application as amended herein.

Respectfully submitted,

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Appendix I (Amended claims with amendments indicated therein by brackets and underlining)

APPENDIX I

**AMENDED CLAIMS WITH AMENDMENTS INDICATED THEREIN
BY BRACKETS AND UNDERLINING**

7. (Amended) The semiconductor temperature detecting circuit according to [any one of Claims 2 through 6] Claim 3:

wherein the semiconductor substrate is of a conductive type of a P type or an N type.